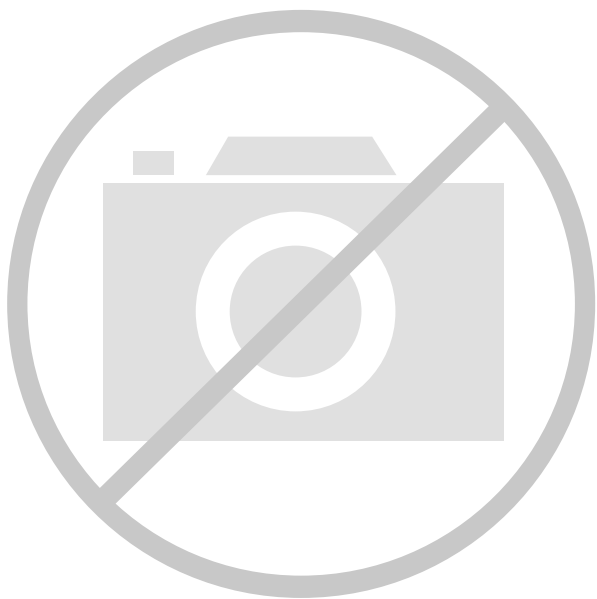




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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	36864
Number of I/O	151
Number of Gates	250000
Voltage - Supply	1.14V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	208-BFQFP
Supplier Device Package	208-PQFP (28x28)
Purchase URL	https://www.e-xfl.com/product-detail/microsemi/a3p250l-1pqq208i

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Array Coordinates

During many place-and-route operations in the Microsemi Designer software tool, it is possible to set constraints that require array coordinates. Table 1-2 provides array coordinates of core cells and memory blocks for IGLOO and ProASIC3 devices. Table 1-3 provides the information for IGLOO PLUS devices. Table 1-4 on page 17 provides the information for IGLOO nano and ProASIC3 nano devices. The array coordinates are measured from the lower left (0, 0). They can be used in region constraints for specific logic groups/blocks, designated by a wildcard, and can contain core cells, memories, and I/Os.

I/O and cell coordinates are used for placement constraints. Two coordinate systems are needed because there is not a one-to-one correspondence between I/O cells and core cells. In addition, the I/O coordinate system changes depending on the die/package combination. It is not listed in Table 1-2. The Designer ChipPlanner tool provides the array coordinates of all I/O locations. I/O and cell coordinates are used for placement constraints. However, I/O placement is easier by package pin assignment.

Figure 1-9 on page 17 illustrates the array coordinates of a 600 k gate device. For more information on how to use array coordinates for region/placement constraints, see the *Designer User's Guide* or online help (available in the software) for software tools.

Table 1-2 • IGLOO and ProASIC3 Array Coordinates

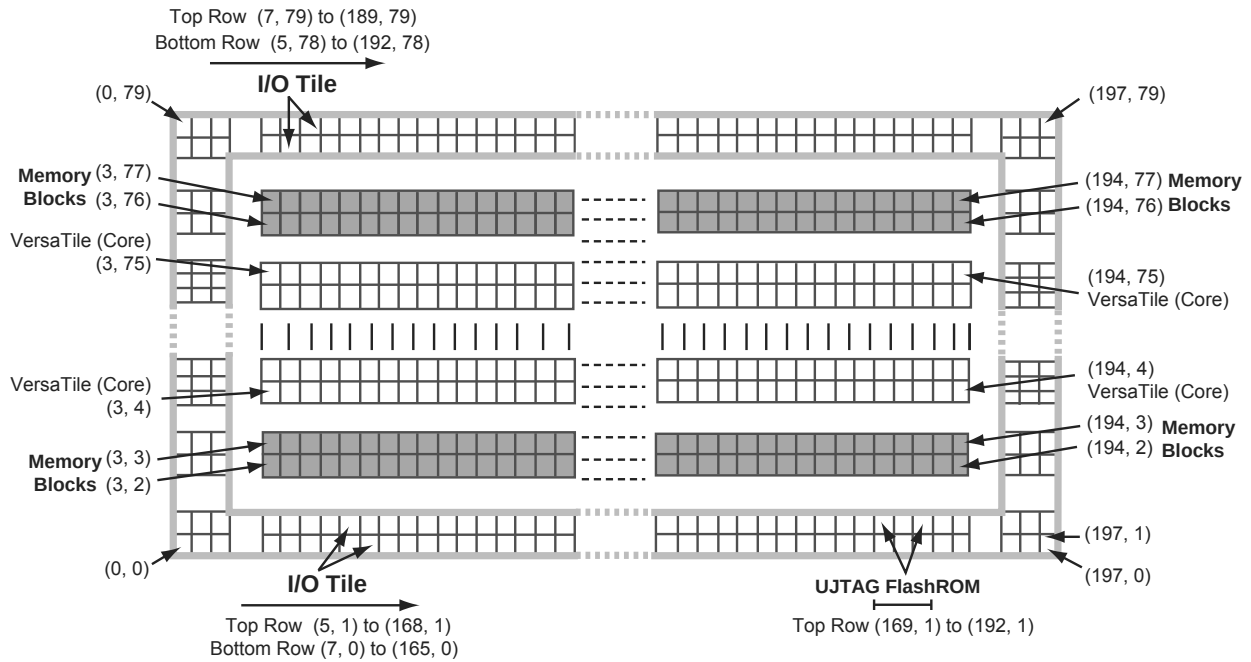
Device		VersaTiles				Memory Rows		Entire Die	
		Min.		Max.		Bottom	Top	Min.	Max.
IGLOO	ProASIC3/ ProASIC3L	x	y	x	y	(x, y)	(x, y)	(x, y)	(x, y)
AGL015	A3P015	3	2	34	13	None	None	(0, 0)	(37, 15)
AGL030	A3P030	3	3	66	13	None	None	(0, 0)	(69, 15)
AGL060	A3P060	3	2	66	25	None	(3, 26)	(0, 0)	(69, 29)
AGL125	A3P125	3	2	130	25	None	(3, 26)	(0, 0)	(133, 29)
AGL250	A3P250/L	3	2	130	49	None	(3, 50)	(0, 0)	(133, 53)
AGL400	A3P400	3	2	194	49	None	(3, 50)	(0, 0)	(197, 53)
AGL600	A3P600/L	3	4	194	75	(3, 2)	(3, 76)	(0, 0)	(197, 79)
AGL1000	A3P1000/L	3	4	258	99	(3, 2)	(3, 100)	(0, 0)	(261, 103)
AGLE600	A3PE600/L, RT3PE600L	3	4	194	75	(3, 2)	(3, 76)	(0, 0)	(197, 79)
	A3PE1500	3	4	322	123	(3, 2)	(3, 124)	(0, 0)	(325, 127)
AGLE3000	A3PE3000/L, RT3PE3000L	3	6	450	173	(3, 2) or (3, 4)	(3, 174) or (3, 176)	(0, 0)	(453, 179)

Table 1-3 • IGLOO PLUS Array Coordinates

Device		VersaTiles				Memory Rows		Entire Die	
		Min.		Max.		Bottom	Top	Min.	Max.
IGLOO PLUS		x	y	x	y	(x, y)	(x, y)	(x, y)	(x, y)
AGLP030		2	3	67	13	None	None	(0, 0)	(69, 15)
AGLP060		2	2	67	25	None	(3, 26)	(0, 0)	(69, 29)
AGLP125		2	2	131	25	None	(3, 26)	(0, 0)	(133, 29)

Table 1-4 • IGLOO nano and ProASIC3 nano Array Coordinates

Device		VersaTiles		Memory Rows		Entire Die	
		Min.	Max.	Bottom	Top	Min.	Max.
IGLOO nano	ProASIC3 nano	(x, y)	(x, y)	(x, y)	(x, y)	(x, y)	(x, y)
AGLN010	A3P010	(0, 2)	(32, 5)	None	None	(0, 0)	(34, 5)
AGLN015	A3PN015	(0, 2)	(32, 9)	None	None	(0, 0)	(34, 9)
AGLN020	A3PN020	(0, 2)	32, 13)	None	None	(0, 0)	(34, 13)
AGLN060	A3PN060	(3, 2)	(66, 25)	None	(3, 26)	(0, 0)	(69, 29)
AGLN125	A3PN125	(3, 2)	(130, 25)	None	(3, 26)	(0, 0)	(133, 29)
AGLN250	A3PN250	(3, 2)	(130, 49)	None	(3, 50)	(0, 0)	(133, 49)



Note: The vertical I/O tile coordinates are not shown. West-side coordinates are {(0, 2) to (2, 2)} to {(0, 77) to (2, 77)}; east-side coordinates are {(195, 2) to (197, 2)} to {(195, 77) to (197, 77)}.

Figure 1-9 • Array Coordinates for AGL600, AGL600, A3P600, and A3PE600

Clock Gating Block

Once DONE_HOUSEKEEPING is detected, the FSM will initiate the clock gating circuit by asserting ASSERT_GATE (active Low). ASSERT_GATE is named control_user_clock_net in the IP block. Upon assertion of the ASSERT_GATE signal, the clock will be gated in less than two cycles. The clock gating circuit is comprised of a flip-flop, latch, AND gate, and CLKINT, as shown in Figure 2-12. The clock gating block can support gating of up to 17 clocks.

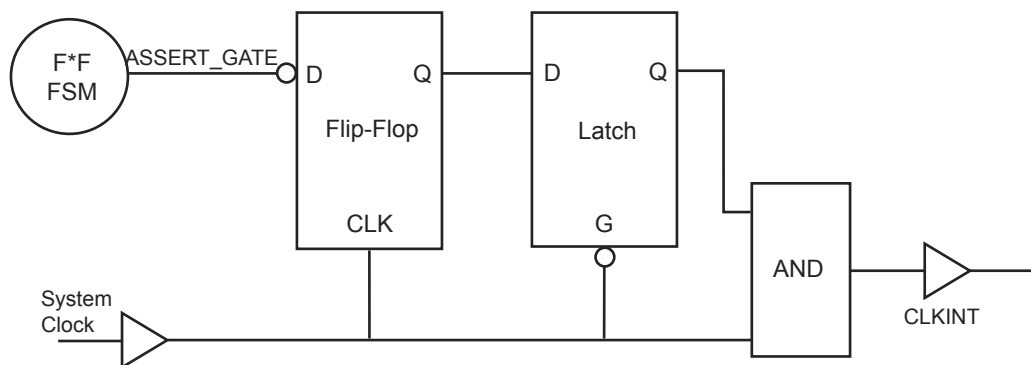


Figure 2-12 • Clock Gating Circuit

After initiating the clock gating circuit, the FSM will assert and hold the LSICC signal (active High), feeding the ULSICC macro. This will initiate the 1 μ s entrance into Flash*Freeze mode.

Upon deassertion of the Flash*Freeze pin, the FSM will set ASSERT_GATE High. Once the I/O banks become active, the clock will enter the device and register the ASSERT_GATE signal, cleanly releasing the clock gate.

Design Flow¹

Microsemi has developed a convenient and intuitive design flow for configuring and integrating Flash*Freeze technology into an FPGA design. Flash*Freeze type 1 is implemented by instantiating the INBUF_FF macro in the top level of a design. Flash*Freeze type 2 with management IP can be generated by the Libero core generator or SmartGen and instantiated as a single block in the user's design. This single block will include an INBUF_FF macro and the optional Flash*Freeze management IP, which includes the ULSICC macro. If designers do not wish to use this core generator, the INBUF_FF macro and the optional ULSICC macro may be instantiated in the design, and custom Flash*Freeze management IP can be developed by the user. The remainder of this section will cover configuration details of the INBUF_FF macro, the ULSICC macro, and the Flash*Freeze management IP.

Additional information on the tools discussed within this section may be found in the Libero online help.

INBUF_FF

The INBUF_FF macro is a special-purpose input buffer macro that is interpreted downstream in the design flow by Microsemi's Designer software. When this macro is used, the top-level port will be forced to the dedicated FF pin in the FPGA, and Flash*Freeze mode will be available for use in the device. The following are the design rules for INBUF_FF:

- If INBUF_FF is not used in the design, the device will not be configured to support Flash*Freeze mode.
- When the INBUF_FF macro is used, the FF pin will establish a hardwired connection to the Flash*Freeze technology circuit in the device, as shown in Figure 2-1 on page 25, Figure 2-3 on page 27, and Figure 2-10 on page 37, and described in the "Flash*Freeze Type 1: Control by Dedicated Flash*Freeze Pin" section on page 24.

1. This section applies to Libero / Designer software v8.3 and later. Microsemi recommends that designs created in earlier versions of the software be modified to accommodate this flow by instantiating the INBUF_FF macro or the Flash*Freeze management IP. Refer to the Libero / Designer software v8.3 release notes and the Libero online help for more information on migrating designs from older software versions.

Design Recommendations

The following sections provide design flow recommendations for using a global network in a design.

- "Global Macros and I/O Standards"
- "Global Macro and Placement Selections" on page 64
- "Using Global Macros in Synplicity" on page 66
- "Global Promotion and Demotion Using PDC" on page 67
- "Spine Assignment" on page 68
- "Designer Flow for Global Assignment" on page 69
- "Simple Design Example" on page 71
- "Global Management in PLL Design" on page 73
- "Using Spines of Occupied Global Networks" on page 74

Global Macros and I/O Standards

The larger low power flash devices have six chip global networks and four quadrant global networks. However, the same clock macros are used for assigning signals to chip globals and quadrant globals. Depending on the clock macro placement or assignment in the Physical Design Constraint (PDC) file or MultiView Navigator (MVN), the signal will use the chip global network or quadrant network. Table 3-8 lists the clock macros available for low power flash devices. Refer to the *IGLOO*, *ProASIC3*, *SmartFusion*, and *Fusion Macro Library Guide* for details.

Table 3-8 • Clock Macros

Macro Name	Description	Symbol
CLKBUF	Input macro for Clock Network	
CLKBUF_x	Input macro for Clock Network with specific I/O standard	
CLKBUF_LVDS/LVPECL	LVDS or LVPECL input macro for Clock Network (not supported for IGLOO nano or ProASIC3 nano devices)	
CLKINT	Macro for internal clock interface	
CLKBIBUF	Bidirectional macro with input dedicated to routed Clock Network	

Use these available macros to assign a signal to the global network. In addition to these global macros, PLL and CLKDLY macros can also drive the global networks. Use I/O-standard-specific clock macros (CLKBUF_x) to instantiate a specific I/O standard for the global signals. Table 3-9 on page 63 shows the list of these I/O-standard-specific macros. Note that if you use these I/O-standard-specific clock macros, you cannot change the I/O standard later in the design stage. If you use the regular CLKBUF macro, you can use MVN or the PDC file in Designer to change the I/O standard. The default I/O

External I/O or Local signal as Clock Source

External I/O refers to regular I/O pins are labeled with the I/O convention IOuxwByVz. You can allow the external I/O or internal signal to access the global. To allow the external I/O or internal signal to access the global network, you need to instantiate the CLKINT macro. Refer to Figure 3-4 on page 51 for an example illustration of the connections. Instead of using CLKINT, you can also use PDC to promote signals from external I/O or internal signal to the global network. However, it may cause layout issues because of synthesis logic replication. Refer to the "Global Promotion and Demotion Using PDC" section on page 67 for details.

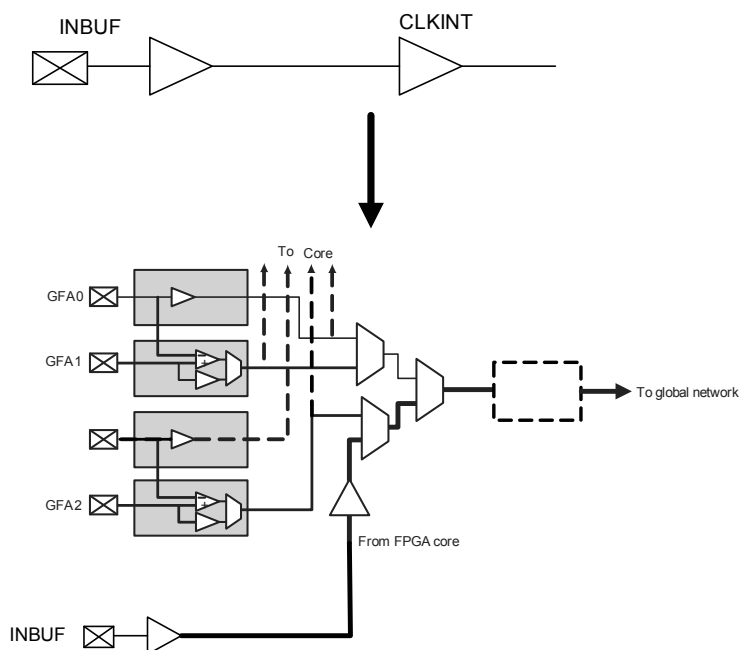


Figure 3-14 • CLKINT Macro

Using Global Macros in Synplicity

The Synplify® synthesis tool automatically inserts global buffers for nets with high fanout during synthesis. By default, Synplicity® puts six global macros (CLKBUF or CLKINT) in the netlist, including any global instantiation or PLL macro. Synplify always honors your global macro instantiation. If you have a PLL (only primary output is used) in the design, Synplify adds five more global buffers in the netlist. Synplify uses the following global counting rule to add global macros in the netlist:

1. CLKBUF: 1 global buffer
2. CLKINT: 1 global buffer
3. CLKDLY: 1 global buffer
4. PLL: 1 to 3 global buffers
 - GLA, GLB, GLC, YB, and YC are counted as 1 buffer.
 - GLB or YB is used or both are counted as 1 buffer.
 - GLC or YC is used or both are counted as 1 buffer.

During Layout, Designer will assign two of the signals to quadrant global locations.

Step 3 (optional)

You can also assign the QCLK1_c and QCLK2_c nets to quadrant regions using the following PDC commands:

```
assign_local_clock -net QCLK1_c -type quadrant UL
assign_local_clock -net QCLK2_c -type quadrant LL
```

Step 4

Import this PDC with the netlist and run Compile again. You will see the following in the Compile report:

The following nets have been assigned to a global resource:

Fanout	Type	Name
1536	INT_NET	Net : EN_ALL_c Driver: EN_ALL_pad_CLKINT Source: AUTO PROMOTED
1536	SET/RESET_NET	Net : ACLR_c Driver: ACLR_pad_CLKINT Source: AUTO PROMOTED
256	CLK_NET	Net : QCLK3_c Driver: QCLK3_pad_CLKINT Source: AUTO PROMOTED
256	CLK_NET	Net : \$1N14 Driver: \$1I5/Core Source: ESSENTIAL
256	CLK_NET	Net : \$1N12 Driver: \$1I6/Core Source: ESSENTIAL
256	CLK_NET	Net : \$1N10 Driver: \$1I6/Core Source: ESSENTIAL

The following nets have been assigned to a quadrant clock resource using PDC:

Fanout	Type	Name
256	CLK_NET	Net : QCLK1_c Driver: QCLK1_pad_CLKINT Region: quadrant_UL
256	CLK_NET	Net : QCLK2_c Driver: QCLK2_pad_CLKINT Region: quadrant_LL

Step 5

Run Layout.

Global Management in PLL Design

This section describes the legal global network connections to PLLs in the low power flash devices. For detailed information on using PLLs, refer to "Clock Conditioning Circuits in Low Power Flash Devices and Mixed Signal FPGAs" section on page 77. Microsemi recommends that you use the dedicated global pins to directly drive the reference clock input of the associated PLL for reduced propagation delays and clock distortion. However, low power flash devices offer the flexibility to connect other signals to reference clock inputs. Each PLL is associated with three global networks (Figure 3-5 on page 52). There are some limitations, such as when trying to use the global and PLL at the same time:

- If you use a PLL with only primary output, you can still use the remaining two free global networks.
- If you use three globals associated with a PLL location, you cannot use the PLL on that location.
- If the YB or YC output is used standalone, it will occupy one global, even though this signal does not go to the global network.

Using Spines of Occupied Global Networks

When a signal is assigned to a global network, the flash switches are programmed to set the MUX select lines (explained in the "Clock Aggregation Architecture" section on page 61) to drive the spines of that network with the global net. However, if the global net is restricted from reaching into the scope of a spine, the MUX drivers of that spine are available for other high-fanout or critical signals (Figure 3-20).

For example, if you want to limit the CLK1_c signal to the left half of the chip and want to use the right side of the same global network for CLK2_c, you can add the following PDC commands:

```
define_region -name region1 -type inclusive 0 0 34 29
assign_net_macros region1 CLK1_c
assign_local_clock -net CLK2_c -type chip B2
```

Figure 3-20 • Design Example Using Spines of Occupied Global Networks

Conclusion

IGLOO, Fusion, and ProASIC3 devices contain 18 global networks: 6 chip global networks and 12 quadrant global networks. These global networks can be segmented into local low-skew networks called spines. The spines provide low-skew networks for the high-fanout signals of a design. These allow you up to 252 different internal/external clocks in an A3PE3000 device. This document describes the architecture for the global network, plus guidelines and methodologies in assigning signals to globals and spines.

Related Documents

User's Guides

IGLOO, ProASIC3, SmartFusion, and Fusion Macro Library Guide
http://www.microsemi.com/soc/documents/pa3_libguide_ug.pdf

Core Logic Clock Source

Core logic refers to internal routed nets. Internal routed signals access the CCC via the FPGA Core Fabric. Similar to the External I/O option, whenever the clock source comes internally from the core itself, the routed signal is instantiated with a PLLINT macro before connecting to the CCC clock input (see Figure 4-12 for an example illustration of the connections, shown in red).

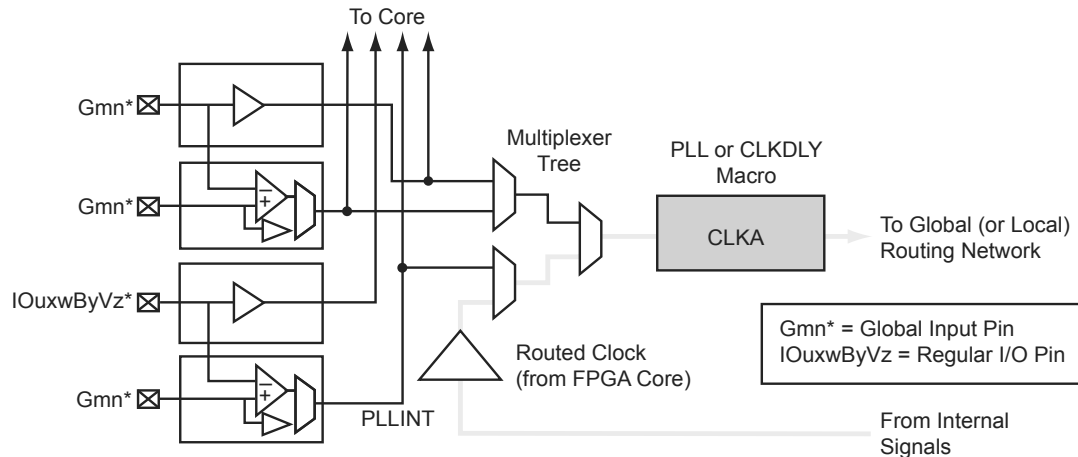


Figure 4-12 • Illustration of Core Logic Usage

For Fusion devices, the input reference clock can also be from the embedded RC oscillator and crystal oscillator. In this case, the CCC configuration is the same as the hardwired I/O clock source, and users are required to instantiate the RC oscillator or crystal oscillator macro and connect its output to the input reference clock of the CCC block.

External Feedback Configuration

For certain applications, such as those requiring generation of PCB clocks that must be matched with existing board delays, it is useful to implement an external feedback, EXTFB. The Phase Detector of the PLL core will receive CLKA and EXTFB as inputs. EXTFB may be processed by the fixed System Delay element as well as the *M* divider element. The EXTFB option is currently not supported.

After setting all the required parameters, users can generate one or more PLL configurations with HDL or EDIF descriptions by clicking the **Generate** button. SmartGen gives the option of saving session results and messages in a log file:

Macro Parameters

```
Name                : test_pll
Family              : ProASIC3E
Output Format       : VHDL
Type               : Static PLL
Input Freq(MHz)    : 10.000
CLKA Source        : Hardwired I/O
Feedback Delay Value Index : 1
Feedback Mux Select : 2
XDLY Mux Select    : No
Primary Freq(MHz)  : 33.000
Primary PhaseShift : 0
Primary Delay Value Index : 1
Primary Mux Select : 4
Secondary1 Freq(MHz) : 66.000
Use GLB            : YES
Use YB             : YES
GLB Delay Value Index : 1
YB Delay Value Index : 1
Secondary1 PhaseShift : 0
Secondary1 Mux Select : 4
Secondary2 Freq(MHz) : 101.000
Use GLC            : YES
Use YC             : NO
GLC Delay Value Index : 1
YC Delay Value Index : 1
Secondary2 PhaseShift : 0
Secondary2 Mux Select : 4
```

...

...

...

```
Primary Clock frequency 33.333
Primary Clock Phase Shift 0.000
Primary Clock Output Delay from CLKA 0.180
```

```
Secondary1 Clock frequency 66.667
Secondary1 Clock Phase Shift 0.000
Secondary1 Clock Global Output Delay from CLKA 0.180
Secondary1 Clock Core Output Delay from CLKA 0.625
```

```
Secondary2 Clock frequency 100.000
Secondary2 Clock Phase Shift 0.000
Secondary2 Clock Global Output Delay from CLKA 0.180
```

Below is an example Verilog HDL description of a legal PLL core configuration generated by SmartGen:

```
module test_pll(POWERDOWN,CLKA,LOCK,GLA);
input POWERDOWN, CLKA;
output LOCK, GLA;
```

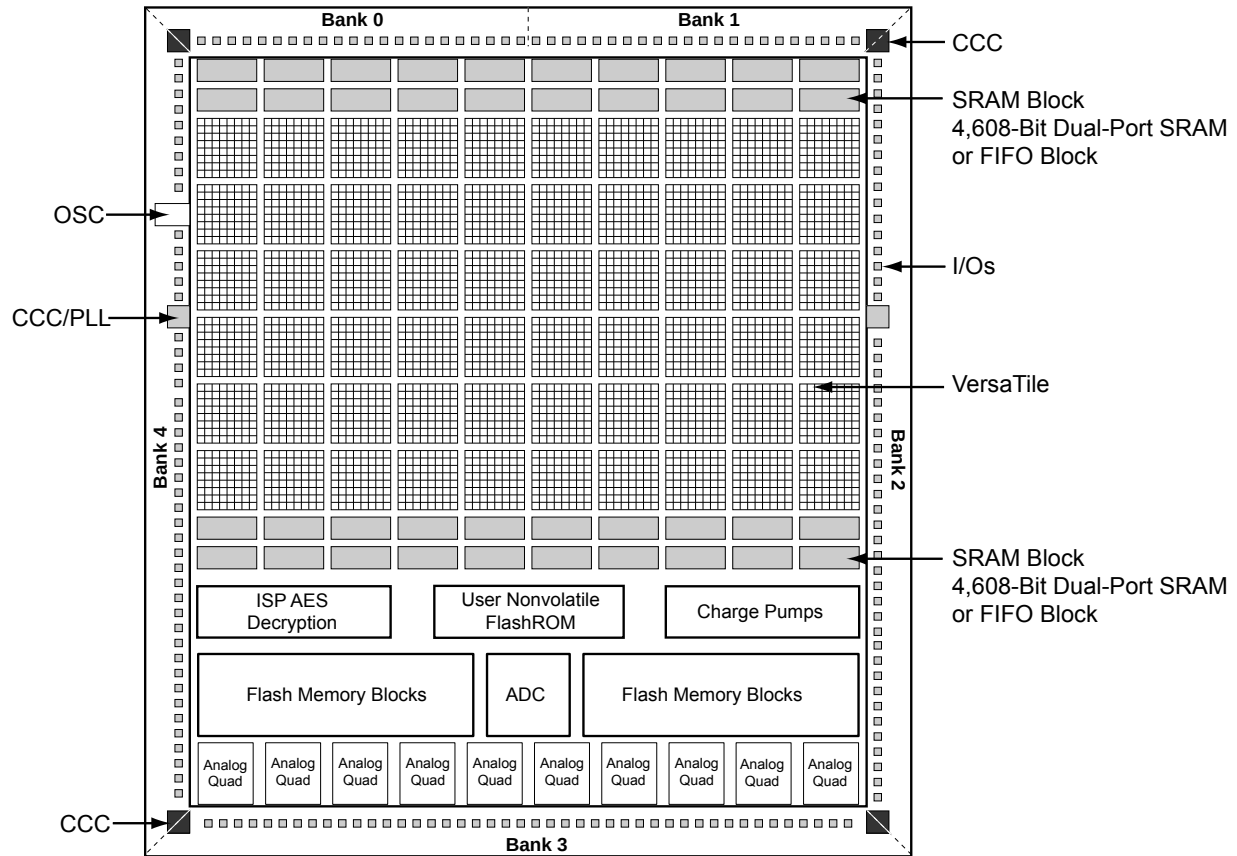


Figure 5-2 • Fusion Device Architecture Overview (AFS600)

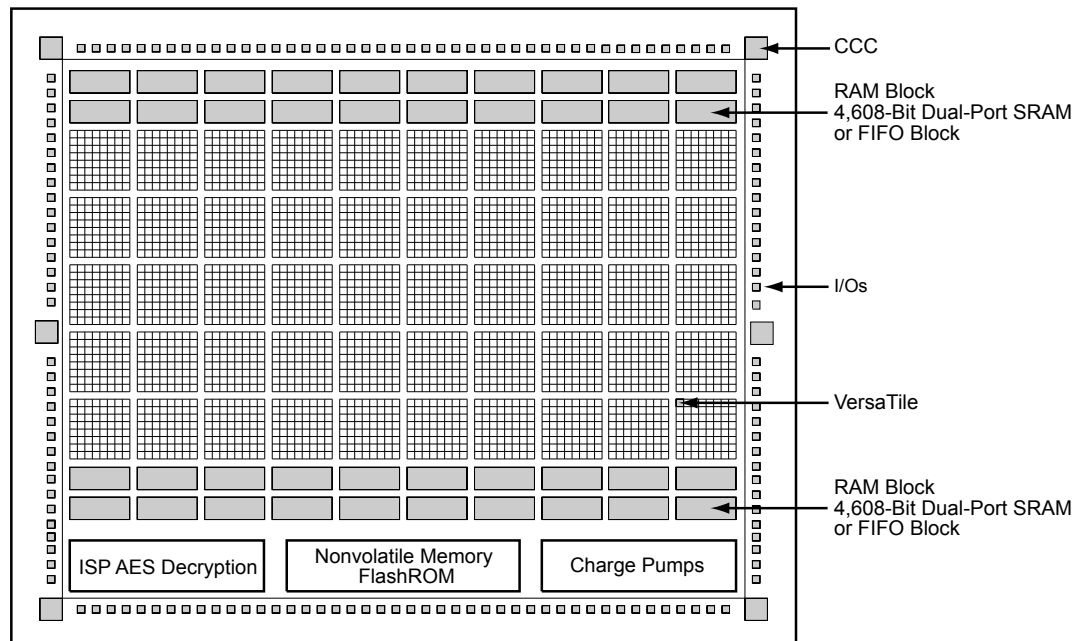


Figure 5-3 • ProASIC3 and IGLOO Device Architecture

compatible, which means devices can operate at conventional PCI frequencies (33 MHz and 66 MHz). PCI-X is more fault-tolerant than PCI. It also does not have programmable drive strength.

Voltage-Referenced Standards

I/Os using these standards are referenced to an external reference voltage (VREF) and are supported on E devices only.

HSTL Class I and II (High-Speed Transceiver Logic)

These are general-purpose, high-speed 1.5 V bus standards (EIA/JESD 8-6) for signaling between integrated circuits. The signaling range is 0 V to 1.5 V, and signals can be either single-ended or differential. HSTL requires a differential amplifier input buffer and a push-pull output buffer. The reference voltage (VREF) is 0.75 V. These standards are used in the memory bus interface with data switching capability of up to 400 MHz. The other advantages of these standards are low power and fewer EMI concerns.

HSTL has four classes, of which low power flash devices support Class I and II. These classes are defined by standard EIA/JESD 8-6 from the Electronic Industries Alliance (EIA):

- Class I – Unterminated or symmetrically parallel-terminated
- Class II – Series-terminated
- Class III – Asymmetrically parallel-terminated
- Class IV – Asymmetrically double-parallel-terminated

SSTL2 Class I and II (Stub Series Terminated Logic 2.5 V)

These are general-purpose 2.5 V memory bus standards (JESD 8-9) for driving transmission lines, designed specifically for driving the DDR SDRAM modules used in computer memory. SSTL2 requires a differential amplifier input buffer and a push-pull output buffer. The reference voltage (VREF) is 1.25 V.

SSTL3 Class I and II (Stub Series Terminated Logic 3.3 V)

These are general-purpose 3.3 V memory bus standards (JESD 8-8) for driving transmission lines. SSTL3 requires a differential amplifier input buffer and a push-pull output buffer. The reference voltage (VREF) is 1.5 V.

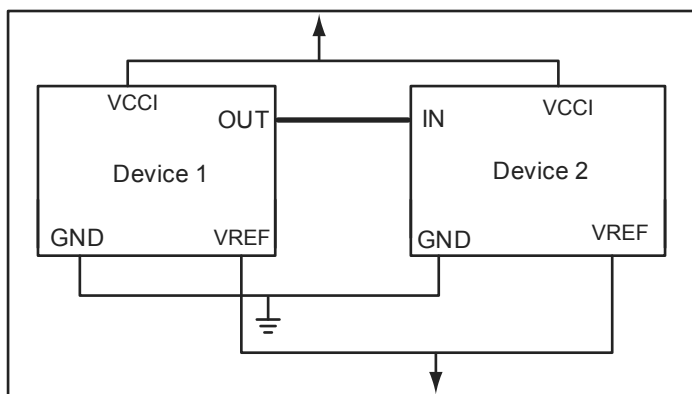


Figure 8-7 • SSTL and HSTL Topology

GTL 2.5 V (Gunning Transceiver Logic 2.5 V)

This is a low power standard (JESD 8-3) for electrical signals used in CMOS circuits that allows for low electromagnetic interference at high transfer speeds. It has a voltage swing between 0.4 V and 1.2 V and typically operates at speeds of between 20 and 40 MHz. VCCI must be connected to 2.5 V. The reference voltage (VREF) is 0.8 V.

GTL 3.3 V (Gunning Transceiver Logic 3.3 V)

This is the same as GTL 2.5 V above, except VCCI must be connected to 3.3 V.

GTL+ (Gunning Transceiver Logic Plus)

This is an enhanced version of GTL that has defined slew rates and higher voltage levels. It requires a differential amplifier input buffer and an open-drain output buffer. Even though the output is open-drain, VCCI must be connected to either 2.5 V or 3.3 V. The reference voltage (VREF) is 1 V.

Differential Standards

These standards require two I/Os per signal (called a "signal pair"). Logic values are determined by the potential difference between the lines, not with respect to ground. This is why differential drivers and receivers have much better noise immunity than single-ended standards. The differential interface standards offer higher performance and lower power consumption than their single-ended counterparts. Two I/O pins are used for each data transfer channel. Both differential standards require resistor termination.

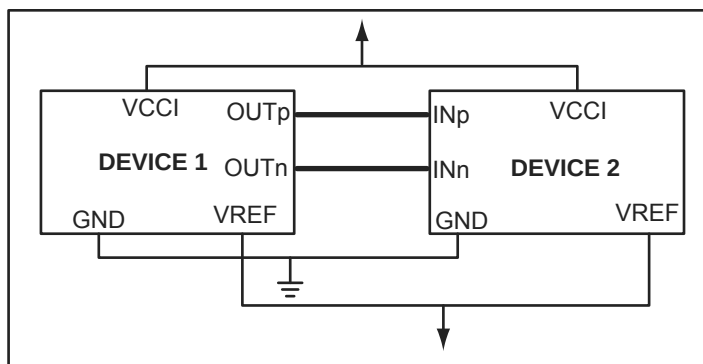


Figure 8-8 • Differential Topology

LVPECL (Low-Voltage Positive Emitter Coupled Logic)

LVPECL requires that one data bit be carried through two signal lines; therefore, two pins are needed per input or output. It also requires external resistor termination. The voltage swing between the two signal lines is approximately 850 mV. When the power supply is +3.3 V, it is commonly referred to as Low-Voltage PECL (LVPECL). Refer to the device datasheet for the full implementation of the LVPECL transmitter and receiver.

LVDS (Low-Voltage Differential Signal)

LVDS is a moderate-speed differential signaling system, in which the transmitter generates two different voltages that are compared at the receiver. LVDS uses a differential driver connected to a terminated receiver through a constant-impedance transmission line. It requires that one data bit be carried through two signal lines; therefore, the user will need two pins per input or output. It also requires external resistor termination. The voltage swing between the two signal lines is approximately 350 mV. VCCI is 2.5 V. Low power flash devices contain dedicated circuitry supporting a high-speed LVDS standard that has its own user specification. Refer to the device datasheet for the full implementation of the LVDS transmitter and receiver.

Solution 3

The board-level design must ensure that the reflected waveform at the pad does not exceed the voltage overshoot/undershoot limits provided in the datasheet. This is a requirement to ensure long-term reliability.

This scheme will also work for a 3.3 V PCI/PCI-X configuration, but the internal diode should not be used for clamping, and the voltage must be limited by the bus switch, as shown in Figure 8-12. Relying on the diode clamping would create an excessive pad DC voltage of $3.3\text{ V} + 0.7\text{ V} = 4\text{ V}$.

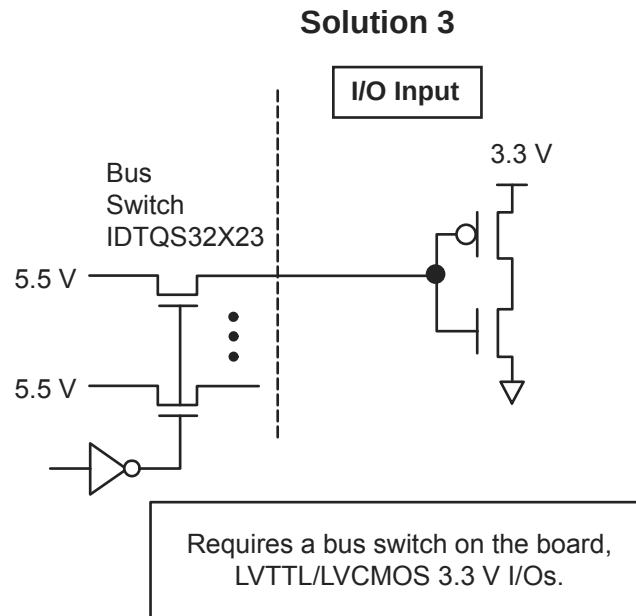


Figure 8-12 • Solution 3

Table 9-3 • PDC I/O Constraints (continued)

Command	Action	Example	Comment
I/O Attribute Constraint			
set_io	Sets the attributes of an I/O	<pre>set_io portname [-pinname value] [-fixed value] [-iostd value] [-out_drive value] [-slew value] [-res_pull value] [-schmitt_trigger value] [-in_delay value] [-skew value] [-out_load value] [-register value] set_io IN2 -pinname 28 -fixed yes -iostd LVCMOS15 -out_drive 12 -slew high -RES_PULL None -SCHMITT_TRIGGER Off -IN_DELAY Off -skew off -REGISTER No</pre>	If the I/O macro is generic (e.g., INBUF) or technology-specific (INBUF_LVCMOS25), then all I/O attributes can be assigned using this constraint. If the netlist has an I/O macro that specifies one of its attributes, that attribute cannot be changed using this constraint, though other attributes can be changed. Example: OUTBUF_S_24 (low slew, output drive 24 mA) Slew and output drive cannot be changed.
I/O Region Placement Constraints			
define_region	Defines either a rectangular region or a rectilinear region	<pre>define_region -name [region_name] -type [region_type] x1 y1 x2 y2 define_region -name test -type inclusive 0 15 2 29</pre>	If any number of I/Os must be assigned to a particular I/O region, such a region can be created with this constraint.
assign_region	Assigns a set of macros to a specified region	<pre>assign_region [region name] [macro_name...] assign_region test U12</pre>	This constraint assigns I/O macros to the I/O regions. When assigning an I/O macro, PDC naming conventions must be followed if the macro name contains special characters; e.g., if the macro name is \\\$1I19\\, the correct use of escape characters is \\\\$1I19\\.

Note: Refer to the Libero SoC User's Guide for detailed rules on PDC naming and syntax conventions.

Related Documents

Below is a list of related documents, their location on the Microsemi SoC Products Group website, and a brief summary of each document.

Application Notes

Programming Antifuse Devices

http://www.microsemi.com/soc/documents/AntifuseProgram_AN.pdf

Implementation of Security in Actel's ProASIC and ProASIC^{PLUS} Flash-Based FPGAs

http://www.microsemi.com/soc/documents/Flash_Security_AN.pdf

User's Guides

FlashPro Programmers

FlashPro4,¹ FlashPro3, FlashPro Lite, and FlashPro²

http://www.microsemi.com/soc/products/hardware/program_debug/flashpro/default.aspx

FlashPro User's Guide

http://www.microsemi.com/soc/documents/FlashPro_UG.pdf

The FlashPro User's Guide includes hardware and software setup, self-test instructions, use instructions, and a troubleshooting / error message guide.

Silicon Sculptor 3 and Silicon Sculptor II

http://www.microsemi.com/soc/products/hardware/program_debug/ss/default.aspx

Other Documents

<http://www.microsemi.com/soc/products/solutions/security/default.aspx#flashlock>

The security resource center describes security in Microsemi Flash FPGAs.

Quality and Reliability Guide

<http://www.microsemi.com/soc/documents/RelGuide.pdf>

Programming and Functional Failure Guidelines

http://www.microsemi.com/soc/documents/FA_Policies_Guidelines_5-06-00002.pdf

1. FlashPro4 replaced FlashPro3 in Q1 2010.
2. FlashPro is no longer available.

Generating Programming Files

Generation of the Programming File in a Trusted Environment— Application 1

As discussed in the "Application 1: Trusted Environment" section on page 309, in a trusted environment, the user can choose to program the device with plaintext bitstream content. It is possible to use plaintext for programming even when the FlashLock Pass Key option has been selected. In this application, it is not necessary to employ AES encryption protection. For AES encryption settings, refer to the next sections.

The generated programming file will include the security setting (if selected) and the plaintext programming file content for the FPGA array, FlashROM, and/or FBs. These options are indicated in Table 12-2 and Table 12-3.

Table 12-2 • IGLOO and ProASIC3 Plaintext Security Options, No AES

Security Protection	FlashROM Only	FPGA Core Only	Both FlashROM and FPGA
No AES / no FlashLock	✓	✓	✓
FlashLock only	✓	✓	✓
AES and FlashLock	–	–	–

Table 12-3 • Fusion Plaintext Security Options

Security Protection	FlashROM Only	FPGA Core Only	FB Core Only	All
No AES / no FlashLock	✓	✓	✓	✓
FlashLock	✓	✓	✓	✓
AES and FlashLock	–	–	–	–

Note: For all instructions, the programming of Flash Blocks refers to Fusion only.

For this scenario, generate the programming file as follows:

1. Select the **Silicon features to be programmed** (Security Settings, FPGA Array, FlashROM, Flash Memory Blocks), as shown in Figure 12-10 on page 314 and Figure 12-11 on page 314. Click **Next**.

If **Security Settings** is selected (i.e., the FlashLock security Pass Key feature), an additional dialog will be displayed to prompt you to select the security level setting. If no security setting is selected, you will be directed to Step 3.

Table 12-5 • FlashLock Security Options for Fusion

Security Option	FlashROM Only	FPGA Core Only	FB Core Only	All
No AES / no FlashLock	–	–	–	–
FlashLock	✓	✓	✓	✓
AES and FlashLock	✓	✓	✓	✓

For this scenario, generate the programming file as follows:

1. Select only the **Security settings** option, as indicated in Figure 12-14 and Figure 12-15 on page 318. Click **Next**.

Figure 12-14 • Programming IGLOO and ProASIC3 Security Settings Only

3. VCC switches from 1.5 V to 1.2 V when TRST is LOW.
-

Figure 14-4 • TRST Toggled LOW

In Figure 14-4, the TRST signal and the VCC core voltage signal are labeled. As TRST is pulled to ground, the core voltage is observed to switch from 1.5 V to 1.2 V. The observed fall time is approximately 2 ms.

DirectC

The above analysis is based on FlashPro3, but there are other solutions to ISP, such as DirectC. DirectC is a microprocessor program that can be run in-system to program Microsemi flash devices. For FlashPro3, TRST is the most convenient control signal to use for the recommended circuit. However, for DirectC, users may use any signal to control the FET. For example, the DirectC code can be edited so that a separate non-JTAG signal can be asserted from the microcontroller that signals the board that it is about to start programming the device. After asserting the N-Channel Digital FET control signal, the programming algorithm must allow sufficient time for the supply to rise to 1.5 V before initiating DirectC programming. As seen in Figure 14-3 on page 345, 50 ms is adequate time. Depending on the size of the PCB and the capacitance on the VCC supply, results may vary from system to system. Microsemi recommends using a conservative value for the wait time to make sure that the VCC core voltage is at the right level.

Conclusion

For applications using IGLOO and ProASIC3L low power FPGAs and taking advantage of the low core voltage power supplies with less than 1.5 V operation, there must be a way for the core voltage to switch from 1.2 V (or other voltage) to 1.5 V, which is required during in-system programming. The circuit explained in this document illustrates one simple, cost-effective way of handling this requirement. A JTAG signal from the FlashPro3 programmer allows the circuit to sense when programming is in progress, enabling it to switch to the correct core voltage.

Figure 18-3 • I/O State when VCCI Is Powered before VCC

Power-Up to Functional Time

At power-up, device I/Os exit the tristate mode and become functional once the last voltage supply in the power-up sequence (VCCI or VCC) reaches its functional activation level. The power-up-to-functional time is the time it takes for the last supply to power up from zero to its functional level. Note that the functional level of the power supply during power-up may vary slightly within the specification at different ramp-rates. Refer to Table 18-2 for the functional level of the voltage supplies at power-up.

Typical I/O behavior during power-up-to-functional time is illustrated in Figure 18-2 on page 377 and Figure 18-3.

Table 18-2 • Power-Up Functional Activation Levels for VCC and VCCI

Device	VCC Functional Activation Level (V)	VCCI Functional Activation Level (V)
ProASIC3, ProASIC3 nano, IGLOO, IGLOO nano, IGLOO PLUS, and ProASIC3L devices running at VCC = 1.5 V*	0.85 V $\pm$ 0.25 V	0.9 V $\pm$ 0.3 V
IGLOO, IGLOO nano, IGLOO PLUS, and ProASIC3L devices running at VCC = 1.2 V*	0.85 V $\pm$ 0.2 V	0.9 V $\pm$ 0.15 V

Note: *V5 devices will require a 1.5 V VCC supply, whereas V2 devices can utilize either a 1.2 V or 1.5 V VCC.

Microsemi's low power flash devices meet Level 0 LAPU; that is, they can be functional prior to V_{CC} reaching the regulated voltage required. This important advantage distinguishes low power flash devices from their SRAM-based counterparts. SRAM-based FPGAs, due to their volatile technology, require hundreds of milliseconds after power-up to configure the design bitstream before they become functional. Refer to Figure 18-4 on page 379 and Figure 18-5 on page 380 for more information.